

**Search Notes**

Application/Control No.

10/676,652

Examiner

Chase Peers

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2186

**SEARCHED**

Class	Subclass	Date	Examiner
711	103,171, 202,203, 207,209	10/31/2005	CP
707	205	10/31/2005	CP
703	23	10/31/2005	CP
365	51	10/31/2005	CP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched East for terms relating to mapping and wear leveling	10/31/2005	CP
Searched NPL for terms relating to mapping	10/31/2005	CP